

Refine Search

Search Results -

Terms	Documents
L5 and (optimiz\$6 with evaluat\$4)	1

Database:

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Search:

L6

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DATE: Thursday, January 20, 2005 [Printable Copy](#) [Create Case](#)

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side by side

Hit Count Set Name

result set

DB=USPT; THES=ASSIGNEE; PLUR=YES; OP=OR

<u>L6</u>	L5 and (optimiz\$6 with evaluat\$4)	1	<u>L6</u>
<u>L5</u>	L1 and (data near1 calculat\$4)	13	<u>L5</u>
<u>L4</u>	L3 and (data near1 calculat\$4)	1	<u>L4</u>
<u>L3</u>	L1 and (optimiz\$6 with evaluat\$4) and intermediat\$4	17	<u>L3</u>
<u>L2</u>	L1 and (optimiz\$6 with evaluat\$4 with intermediat\$4)	0	<u>L2</u>
<u>L1</u>	(query\$4 with structure with (creat\$6 or generat\$4 or assembl\$4))	444	<u>L1</u>

END OF SEARCH HISTORY

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optimization <and> query <and> calculation <and> e

Search

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